



PTO/SB/08A (08-03)

INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)		Complete if Known	
		Application Number	10/644,844
		Filing Date	August 19, 2003
		First Named Inventor	Henley, Francois J.
		Art Unit	Not Yet Assigned 2823
Examiner Name	Not Yet Assigned H. LEE		
Sheet 1	of 12	Attorney Docket Number	018419-000183US

U.S. PATENT DOCUMENTS*					
Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number Kind Code ² (if known)			
<i>Lee</i>	1	2,614,055	10/1952	Senarclens	
	2	3,117,022	01/1964	Bronson et al.	
	3	3,225,820	12/1995	Riordan	
	4	3,390,033	06/1968	Brown	
	5	3,551,213	12/1970	Boyle	
	6	3,770,499	10/1973	Crowe et al.	
	7	3,786,359	01/1974	King	
	8	3,806,380	04/1974	Kitada et al.	
	9	3,832,219	08/1974	Nelson et al.	
	10	3,900,636	08/1975	Curry et al.	
	11	3,901,423	08/1975	Hillberry et al.	
	12	3,915,757	10/1975	Engel	
	13	3,946,334	03/1976	Yonezu et al.	
	14	3,957,107	05/1976	Altos et al.	
	15	3,993,909	11/1976	Drewe et al.	
	16	4,006,340	02/1977	Gorinas	
	17	4,039,416	08/1977	White	
	18	4,053,335	10/1977	Hu	
	19	4,074,139	02/1978	Pankove	
	20	4,107,350	08/1978	Berg et al.	
	21	4,108,751	08/1978	King	
	22	4,116,751	09/1978	Zarumb	
	23	4,121,334	10/1978	Wallis	
	24	4,170,662	10/1979	Weiss et al.	
	25	4,216,906	08/1980	Olsen et al.	
	26	4,237,601	12/1980	Woolhouse et al.	
	27	4,244,348	01/1981	Wilkes	
	28	4,252,837	02/1981	Auton	
29	4,255,208	03/1981	Deutscher et al.		

Examiner Signature	<i>Kevin Ming Lee</i>	Date Considered	<i>6/22/05</i>
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60070501 v1

paper no. : 012305



Substitute for form 1449A/PTO		Complete if Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)		Application Number	10/644,644
		Filing Date	August 19, 2003
		First Named Inventor	Hanley, Francois J.
		Art Unit	Not Yet Assigned 3823
		Examiner Name	Not Yet Assigned H. LEE
Sheet 2	of 12	Attorney Docket Number	018419-000183US

U.S. PATENT DOCUMENTS*					
Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number Kind Code ² (if known)			
Lee	30	4,274,004	06/1981	Kasai	
	31	4,342,631	08/1982	White et al.	
	32	4,346,123	08/1982	Kaufmann	
	33	4,361,600	11/1982	Brown	
	34	4,368,083	01/1983	Bruei et al.	
	35	4,375,125	03/1983	Byatt	
	36	4,412,868	11/1983	Brown et al.	
	37	4,452,644	06/1984	Bruei et al.	
	38	4,468,309	08/1984	White	
	39	4,471,003	09/1984	Cann	
	40	4,486,247	12/1984	Eccer et al.	
	41	4,490,190	12/1984	Speri	
	42	4,500,563	02/1985	Ellenberger et al.	
	43	4,508,056	04/1985	Bruei et al.	
	44	4,536,657	08/1985	Bruei	
	45	4,539,050	09/1985	Kramler et al.	
	46	4,566,403	01/1986	Fournier	
	47	4,567,505	01/1986	Pease et al.	
	48	4,568,563	02/1986	Jackson et al.	
	49	4,585,945	04/1986	Bruei et al.	
	50	4,645,546	02/1987	Matsushita	
	51	4,684,535	08/1987	Heinecke et al.	
	52	4,704,302	11/1987	Bruei et al.	
	53	4,706,377	11/1987	Shuskus	
	54	4,717,683	01/1988	Parrillo et al.	
	55	4,727,047	02/1988	Bozler et al.	
	56	4,764,394	08/1988	Conrad	
	57	4,766,086	08/1988	Ohshima et al.	
	58	4,837,172	06/1989	Mizuno et al.	

Examiner Signature	<i>How Maj Lee</i>	Date Considered	6/22/05
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60070501 v1



PTO/SB/08A (08-03)

Substitute for form 1449A/PTO		Complete if Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)		Application Number	10/644,644
		Filing Date	August 19, 2003
		First Named Inventor	Henley, Francois J.
		Art Unit	Not Yet Assigned 2523
		Examiner Name	Not Yet Assigned H LEE
Sheet 3	of 12	Attorney Docket Number	018419-000183US

U.S. PATENT DOCUMENTS*					
Examiner Initials*	Cite No. ¹	Document Number Number Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear ³
Lee	59	4,846,928	07/1989	Dofins et al.	
	60	4,847,792	07/1989	Barna et al.	
	61	4,853,250	08/1989	Boulos et al.	
	62	4,883,561	11/1989	Gmitter et al.	
	63	4,887,005	12/1989	Rough et al.	
	64	4,891,329	01/1990	Reisman et al.	
	65	4,894,709	01/1990	Phillips et al.	
	66	4,931,405	06/1990	Kamijo et al.	
	67	4,948,458	08/1990	Ogle	
	68	4,952,273	08/1990	Popov	
	69	4,956,693	09/1990	Sawahata et al.	
	70	4,960,073	10/1990	Suzuki et al.	
	71	4,982,090	01/1991	Wittmaack	
	72	4,983,251	01/1991	Haisma et al.	
	73	4,996,077	02/1991	Moslehi et al.	
	74	5,015,353	05/1991	Hubler et al.	
	75	5,034,343	07/1991	Rouse et al.	
	76	5,070,040	12/1991	Pankove	
	77	5,082,793	01/1992	Li	
	78	5,102,821	04/1992	Moslehi	
	79	5,110,748	05/1992	Sarma	
	80	5,133,826	07/1992	Dandi	
	81	5,162,241	11/1992	Mori et al.	
	82	5,196,355	03/1993	Wittkower	
	83	5,198,371	03/1993	Li	
	84	5,202,095	04/1993	Houchin et al.	
	85	5,203,960	04/1993	Dandi	
	86	5,206,749	04/1993	Zavracky et al.	
Lee	87	5,213,451	05/1993	Frank	
Examiner Signature	Krisen Mary Lee			Date Considered	6/22/05

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PTO/SB02A (03-03)

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**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

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Sheet 4 of 12

Complete if Known

Application Number	10/644,644
Filing Date	August 19, 2003
First Named Inventor	Henley, Francois J.
Art Unit	Not Yet Assigned 2823
Examiner Name	Not Yet Assigned H. LEE
Attorney Docket Number	018419-000183US

U.S. PATENT DOCUMENTS+

Examiner Initials	Cite No. ¹	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² (if known)			
L	88	5,234,529		08/1993	Johnson	
	89	5,234,535		08/1993	Beyer et al.	
	90	5,242,861		09/1993	Inaba	
	91	5,250,328		10/1993	Otto	
	92	5,252,178		10/1993	Moslehi	
	93	5,256,562		10/1993	Vu et al.	
	94	5,258,320		11/1993	Zavracky et al.	
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	96	5,269,880		12/1993	Jolly et al.	
	97	5,273,610		12/1993	Thomas, III et al.	
	98	5,277,748		01/1994	Sakaguchi et al.	
	99	5,303,574		04/1994	Matossian et al.	
	100	5,304,509		04/1994	Sopori	
	101	5,308,776		05/1994	Gotou	
	102	5,317,236		05/1994	Zavracky et al.	
	103	5,342,472		08/1994	Imahashi et al.	
L	104	5,344,524		09/1994	Sharma et al.	
	105	5,354,381		10/1994	Sheng	
	106	5,362,671		11/1994	Zavracky et al.	
	107	5,363,603		11/1994	Miller et al.	
	108	5,368,710		11/1994	Chen et al.	
	109	5,370,765		12/1994	Dandi	
	110	5,374,564		12/1994	Brud	
	111	5,376,560		12/1994	Aronowitz et al.	
	112	5,377,031		12/1994	Vu et al.	
	113	5,404,079		04/1995	Obkuni et al.	
	114	5,405,480		04/1995	Benzing et al.	
	115	5,411,592		05/1995	Ovshinsky et al.	
	116	5,413,679		05/1995	Godbey	

Examiner
SignatureDate
Considered

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**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

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Sheet 5

of 12

C mplate If Known

Application Number	10/644,644
Filing Date	August 19, 2003
First Named Inventor	Henley, Francois J.
Art Unit	Not Yet Assigned 2823
Examiner Name	Not Yet Assigned H. LEE
Attorney Docket Number	018419-000183US

U.S. PATENT DOCUMENTS+

Examiner Initials*	Cite No. ¹	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² (if known)			
Lee	117	5,435,880		07/1995	Minato et al.	
	118	5,438,241		08/1995	Zavracky et al.	
	119	5,443,661		08/1995	Oguro et al.	
	120	5,444,557		08/1995	Spitzer et al.	
	121	5,459,016		10/1995	Debe et al.	
	122	5,475,514		12/1995	Salerno et al.	
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Lee	131	5,559,043		09/1996	Bruehl	
	132	5,569,620		10/1996	Linn et al.	
	133	5,581,385		12/1996	Spitzer et al.	
	134	5,585,304		12/1996	Hayashi et al.	
	135	5,611,855		03/1997	Wijarnakula	
	136	5,643,834		07/1997	Harada et al.	
	137	5,653,811		08/1997	Chan	
	138	5,705,421		01/1998	Matsushita et al.	
	139	5,710,057		01/1998	Kenney	
	140	5,714,395		02/1998	Bruehl	
	141	5,744,852		04/1998	Linn et al.	
	142	5,753,560		05/1998	Hong et al.	
	143	5,755,914		05/1998	Yonchara	
	144	5,763,319		06/1998	Ling et al.	
	145	5,783,022		07/1998	Cha et al.	
Examiner Signature	Karin Ming Lee			Date Considered	6/22/05	

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PTO/SB/08A (03-03)

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**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

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Sheet

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of

12

Complete if Known

Application Number

10/644,644

Filing Date

August 19, 2003

First Named Inventor

Henley, Francois J.

Art Unit

Not Yet Assigned 282J

Examiner Name

Not Yet Assigned H. LEE

Attorney Docket Number

018419-000183US

U.S. PATENT DOCUMENTS*

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		Number	Kind Code ² (if known)			
Lee	146	5,804,086		09/1998	Bruei	
	147	5,821,158		10/1998	Shishiguchi	
	148	5,824,595		10/1998	Igel et al.	
	149	5,827,751		10/1998	Nuyen	
	150	5,840,590		11/1998	Myers, Jr. et al.	
	151	5,854,123		12/1998	Sato et al.	
	152	5,869,387		02/1999	Sato et al.	
	153	5,877,070		03/1999	Goesele et al.	
	154	5,882,987		03/1999	Srikrishnan	
	155	5,909,627		06/1999	Egloff	
	156	5,920,764		07/1999	Hanson et al.	
	157	5,953,622		09/1999	Lee et al.	
	158	5,966,620		10/1999	Sakaguchi et al.	
	159	5,985,742		11/1999	Henley et al.	
	160	5,993,677		11/1999	Biasse et al.	
	161	5,994,207		11/1999	Henley et al.	
	162	6,010,579		01/2000	Henley et al.	
Lee	163	6,013,563		01/2000	Henley et al.	
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	165	6,033,974		03/2000	Henley et al.	
	166	6,048,411		04/2000	Henley et al.	
	167	6,077,383		06/2000	Laporte	
	168	6,083,324		07/2000	Henley	
	169	6,120,597		09/2000	Levy et al.	
	170	6,150,239		11/2000	Goesele et al.	
	171	6,159,824		12/2000	Henley et al.	
	172	6,171,965		01/2001	Kang et al.	
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Examiner
Signature*Kevin Ming Lee*Date
Considered

6/22/05

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PTO/SB/08A (08-03)

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STATEMENT BY APPLICANT**

(use as many sheets as necessary)

Sheet 7

of 12

Complete if Known

Application Number	10/644,644
Filing Date	August 19, 2003
First Named Inventor	Henley, Francois J.
Art Unit	Not Yet Assigned 2.823
Examiner Name	Not Yet Assigned H LEE
Attorney Docket Number	018419-000183US

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		Number	Kind Code ² (if known)			
Lee	174	6,190,998		02/2001	Bruel et al.	
Lee	175	6,191,007		02/2001	Matsui et al.	
Lee	176	6,214,701		04/2001	Matsushita et al.	
Lee	177	6,225,192		05/2001	Aspar et al.	

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Examiner Initials*	Cite No. ¹	Foreign Patent Document			Publication Date MM-DD- YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁴
		Country Code ³	Number ⁴	Kind Code ⁵ (if known)				
Lee	178	DE	0834363		03/1952			
	179	EP	0112 230	A1	04/1987			
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	181	EP	0504714		09/1992			
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	183	EP	0379828		09/1995			
	184	EP	0459177		12/1995			
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	189	EP	0867 917	A2	09/1998			
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	195	EP	164 281	A1	12/1985			
	196	EP	181 249	A1	06/1989			
	197	EP	0355913		12/1993			
	198	EP	0665588		12/1995			
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	201	FR	1558881		01/1969			

Examiner
Signature

Karen Ming Lee

Date
Considered

6/22/05

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60070501 v1



PTO/SB/08A (08-03)

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)		Application Number	10/644,644
		Filing Date	August 19, 2003
		First Named Inventor	Henley, Francois J.
		Art Unit	Not Yet Assigned 2823
		Examiner Name	Not Yet Assigned H. LEG
Sheet 8	of 12	Attorney Docket Number	018419-000183US

Examiner or Initials	Cite No. ¹	Foreign Patent Document			Publication Date MM-DD- YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁴
		Country Code ²	Number ³	Kind Code ⁵ (if known)				
Lee	202	FR	2261802		02/1974			
	203	FR	2235474		04/1974			
	204	FR	2298880		01/1975			
	205	FR	2266304		04/1975			
	206	FR	2519437		01/1982			
	207	FR	2529383		06/1982			
	208	FR	2537768		08/1982			
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	211	FR	2560426		02/1984			
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	215	FR	2714524		12/1993			
	216	FR	2715501		01/1994			
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	221	GB	2221991		07/1989			
	222	GB	2 231 197	A	11/1990			
	223	JP	60-235434		11/1958			
	224	JP	3-109731	A	05/1991			
	225	JP	3-132055	A	06/1991			
226	JP	3-265156	A	11/1991				
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228	JP	11-045840	A	02/1999				
229	JP	53-104156		09/1978				
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231	JP	60-83591		10/1983				
232	JP	59-19394		01/1984				
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Examiner Signature		Date Considered			6/22/05			

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**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

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Sheet 9

of 12

Complete if Known

Application Number	10/644,644
Filing Date	August 19, 2003
First Named Inventor	Henley, Francois J.
Art Unit	Not Yet Assigned 2P23
Examiner Name	Not Yet Assigned H LEE
Attorney Docket Number	018419-000183US

FOREIGN PATENT DOCUMENTS								
Examin or Initials	Cite No. ¹	Foreign Patent Document			Publication Date MM-DD- YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁴
		Country Code ²	Number ³	Kind Code ⁵ (if known)				
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Examiner
Signature*Hee-Myung Lu*Date
Considered*6/22/05*

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Institute for form 1448B/PTO		Compl. to if Known			
		Application Number	10/644,644		
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)		Filing Date	August 19, 2003		
		First Named Inventor	Henley, Francois J.		
		Art Unit	Not Yet Assigned 2823		
		Examiner Name	Not Yet Assigned H. LEE		
Sheet	10	of	12	Attorney Docket Number	018419-000183US

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials *	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
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Examiner Signature	<i>Karon My Lee</i>	Date Considered	6/22/05
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		Filing Date	August 19, 2003
		First Named Inventor	Henley, Francois J.
		Art Unit	Not Yet Assigned 2823
		Examiner Name	Not Yet Assigned H IEE
Sheet 11	of 12	Attorney Docket Number	018419-000183US

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Examiner Signature	<i>Kevin M. Lee</i>	Date Considered	6/22/05
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		Application Number	10/644,644
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)		Filing Date	August 19, 2003
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Examiner Signature	<i>Karen Mary Lee</i>	Date Considered	6/22/05
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